# **Supporting Information for:**

## Crystallographic Investigations into Properties of Acentric Hybrid Perovskite Single Crystals NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br)

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### **Experimental Section**

Figure S1. Schematic illustrations for the growth equipment of bulk  $NH(CH_3)_3SnX_3$  (X= Cl,

Br) single crystals.

Figure S2. The photos of opaque NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X=Cl, Br) single crystals.

**Figure S3.** (a) The powder SHG signal of NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br) compared with KH<sub>2</sub>PO<sub>4</sub> (KDP) (particle size: 75-100  $\mu$  m). (b) Particle size dependence of SHG intensity for NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br).

**Figure S4.** Temperature dependence of the SHG intensity of NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X=CI, Br) measured on crystalline powder samples, compared with the KDP crystalline powder samples.

**Figure S5.** Powder and calculated X-ray diffraction patterns of NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br) at different temperature.

**Figure S6.** Powder and calculated X-ray diffraction patterns of  $NH(CH_3)_3SnX_3$  (X= CI, Br) when exposure to air for one month.

#### **Experimental Section**

Single-Crystal X-ray Diffraction and Powder X-ray diffraction. Single-crystal X-ray diffraction measurements were executed on a *Bruker SMART APEX-II* diffractometer equipped with a CCD detector (graphite-monochromated Mo-Kα radiation,  $\lambda = 0.71073$  Å) at different temperature. Data integration and refinements were carried out with *APEX2* software.<sup>[1]</sup> All the crystal structures were determined by direct methods and refined by full-matrix least-squares on F<sup>2</sup> using the *SHELXTL* program package.<sup>[2]</sup> All the atom displacements in the crystal structure were fixed with anisotropic thermal parameters, and the refinements converged for Fo<sup>2</sup>>2σ (Fo<sup>2</sup>). Symmetry analysis on the model using *PLATON* functions <sup>[3]</sup> of the *WinGX* platform <sup>[4]</sup> showed that no evident space group alternation was required. *ISOTROPY* software<sup>[5]</sup> was used to calculate the group-subgroup relationships and to find the correct space group. X-Ray powder diffraction (XRD) of polycrystalline material taken from the reaction solution was also collected using a *Bruker-AXS D8 ADVANCE X*-Ray diffractometer with Cu-Kα<sub>1</sub> radiation ( $\lambda = 1.54186$  Å) in the range of 10°-90° (2θ) with a time setting of 0.1 second per step and a step length of 0.002°.

*UV-vis diffuse reflectance spectra measurements.* UV-vis diffuse reflectance spectroscopy was carried out using a Shimadzu UV-3101PC spectrophotometer equipped with an integrating sphere over the spectral range 200-800 nm. A BaSO<sub>4</sub> plate was used as the standard (100% reflectance). The absorption spectrum was calculated from the reflectance spectrum using the Kubelka-Munk function:  $F(R) = \alpha/S = (1-R)^2/(2R)$ ,<sup>[6]</sup> where  $\alpha$  is the absorption coefficient, *S* is the scattering coefficient, and R is the reflectance.

**Second-Harmonic Generation (SHG) measurements**. The SHG effect of the NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= Cl, Br) powder samples was investigated using a Kurtz-Perry powder technique.<sup>[7]</sup> A pulsed Q-switched Nd: YAG laser was utilized to generate fundamental 1064 nm light with a pulse width of pulse width of 10 ns, pulse duration of 1 Hz and pulse energy of 10 mJ. Polycrystalline samples of NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= Cl, Br) and KH<sub>2</sub>PO<sub>4</sub> (KDP) were grinded and sieved to obtain distinct grain sizes ranges (40-60, 60-80, 125-175, 225-275, 275-325  $\mu$  m) in Figure S3. Microcrystalline KDP was served as the references. Besides, the temperature-dependent-SHG measurements were described elsewhere.<sup>17, 18</sup>

Thermogravimetric analysis and Differential scanning calorimetry (DSC) measurements. Differential scanning calorimetry (DSC) and thermogravimetric analysis (TGA) were carried out using a TGA/DSC1/1600HT analyzer (*METTLER TOLEDO* Instruments). The NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br) powder samples were placed in a platinum crucible, and heated at a rate of 10 °C min<sup>-1</sup> from room temperature to 800 °C under flowing N<sub>2</sub> gas, respectively. Differential Scan calorimetry (DSC) measurements were performed on Polyma Instruments (*DSC-200-F3 Maia*). The NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br) powder samples were placed in a platinum crucible, and heated at a rate of 10 °C min<sup>-1</sup> from room temperature to 10 °C min<sup>-1</sup> from room temperature to 800 °C under samples were placed in a platinum crucible, and heated at a rate of 10 °C min<sup>-1</sup> from room temperature to 150 °C, and then cooled to -70 °C in liquid N<sub>2</sub> atmosphere and shifted back to room temperature under flowing N<sub>2</sub> gas.

*X-ray photoelectron spectroscopy (XPS) measurements.* XPS measurements of the NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br) on four samples with  $3 \times 3 \times 1 \text{ mm}^3$  (newly synthesized and exposure to air one month) were performed on *ESCALAB* 250 (*ThermoFisher SCIENTIFIC*) instrument under vacuum atmosphere (1.7×10<sup>-10</sup> mbar).

**Band structure calculations.** The initial single crystal structures for NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br) were obtained from single-crystal X-ray crystallographic data. All the calculations were performed using VASP 5.3.3 software <sup>[9-12]</sup> and then the atomic positions were optimized at PBE <sup>[13-14]</sup>/PAW <sup>[15-16]</sup> level with k points set as 2\*2\*2. Based on the optimized structure, the band structure were calculated along the path G (0.0, 0.0, 0.0)-F (0.0, 0.5, 0.0)-Q (0.0, 0.5, 0.5)-Z (0.0, 0.0, 0.5)-G at the same the level of theory.

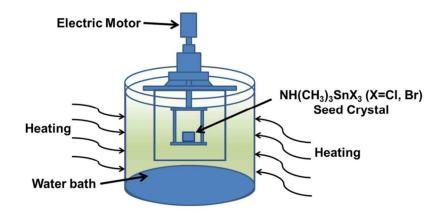


Figure S1. Schematic illustrations for the growth equipment of bulk NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= Cl,

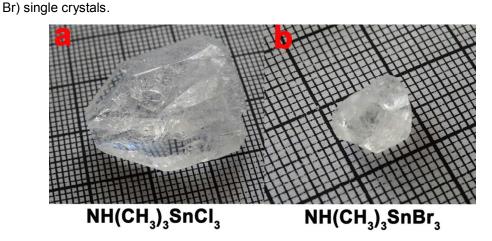
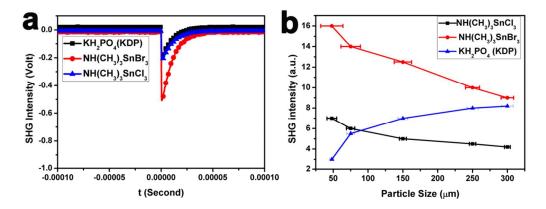
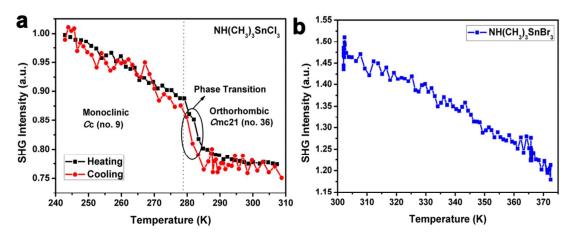


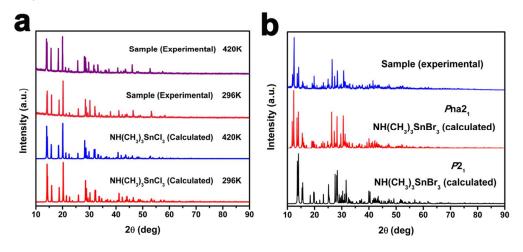
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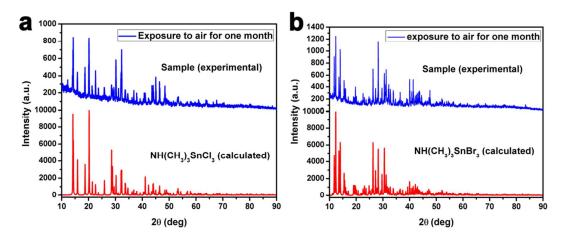
**Figure S3.** (a) The powder SHG signal of NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= Cl, Br) compared with KH<sub>2</sub>PO<sub>4</sub> (KDP) (particle size: 75-100  $\mu$  m). (b) Particle size dependence of SHG intensity for NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= Cl, Br) compared with KH<sub>2</sub>PO<sub>4</sub> (KDP).



**Figure S4.** Temperature dependence of the SHG intensity of  $NH(CH_3)_3SnX_3$  (X=Cl, Br) measured on crystalline powder samples, compared with the KDP crystalline powder samples.



**Figure S5.** Powder and calculated X-ray diffraction patterns of NH(CH<sub>3</sub>)<sub>3</sub>SnX<sub>3</sub> (X= CI, Br). (a) Powder and calculated X-ray diffraction patterns of NH(CH<sub>3</sub>)<sub>3</sub>SnCl<sub>3</sub> at different temperature; (b) Powder and calculated X-ray diffraction patterns with space group Pna2<sub>1</sub> by NH(CH<sub>3</sub>)<sub>3</sub>SnBr<sub>3</sub> single crystal measurements, and calculated X-ray diffraction pattern with space group P2<sub>1</sub> reported by Thiele, et al.<sup>[8]</sup>



**Figure S6.** Powder and calculated X-ray diffraction patterns of  $NH(CH_3)_3SnX_3$  (X= Cl, Br) when exposure to air for one month.

#### References

- [1]Bruker, APEX2, Bruker Analytical X-ray Instruments, Inc., Madison, Wisconsin, USA, 2005.
- [2]Sheldrick, G. M. SHELXTL, version 6.12, Bruker Analytical X-ray Instruments, Inc., Madison, WI, 2001.
- [3]Spek, A. L. J. Appl. Crystallogr., 2003, 36, 7-13.
- [4]Farrugia, L. J. J. Appl. Cryst. 1999, 32, 837-838.
- [5] Stokes H. T.; Hatch, D. M.; Campbell, B. J. *ISOTROPY*; Department of Physics and Astronomy, Brigham Young University: Provo, Utah, 2007; stokes.byu.edu/isotropy.html.
- [6]Wendlandt, W. M.; Hecht, H. G. *Reflectance Spectroscopy*, Interscience, New York, 1966, p. 62.
- [7]Kurtz, S. K. and Perry, T. T. J. Appl. Phys. 1968, 39, 3798-3813.
- [8]Thiele, G.; Seer, B. R. Z. Kristallogr., 1996, 211, 46.
- [9]Kresse, G. and Hafner, J. Phys. Rev. B, 1993, 47, 558-561.
- [10]Kresse G. and Hafner, J. Phys. Rev. B, 1994, 49, 14251-14269.
- [11]Kresse G. and Furthmüller, J. Comput. Mat. Sci., 1996, 6, 15-50
- [12]Kresse G. and Furthmüller, J. Phys. Rev. B, 1996, 54, 11169-11186.
- [13]Perdew, J.; P. Burke, K. and Ernzerhof, M. Phys. Rev. Lett., 1996, 77, 3865-3868.
- [14]Perdew, J.; P. Burke, K. and Ernzerhof, M. Phys. Rev. Lett., 1997, 78, 1396.
- [15]Blochl, P. E. Phys. Rev. B, 1994, 50, 17953-17979.
- [16]Kresse, G. and Joubert, D. Phys. Rev. B, 1999, 59, 1758-1775.
- [17]Ye, H. Y. et al. J. Am. Chem. Soc., 2014,136, 10033-10040.
- [18]Zhang, Y. et al. Angew. Chem. Int. Ed., 2014, 53, 5064-5068.